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PATENT NUMBER and ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10004646	FILING DATE 12/03/2001	CLASS 350 430	SUBCLASS 492.23	GAU 2AB1 4756	EXAMINER J.M.D. KALUODA
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**APPLICANTS: Udagawa Jin;

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:
JAPAN 2000-366847 12/01/2000

PG-PUB <input type="checkbox"/>	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged: Examiners's initials		ATTORNEY DOCKET NO 4641-61503
TITLE : Devices and methods for monitoring respective operating temperatures of components in a microlithography apparatus		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
Assistant Examiner		Total Claims	Print Claim for O.G.
Primary Examiner		DRAWING	
PREPARED FOR ISSUE		Sheets Drawg.	Fig. Drawg.
Application Examiner		Print Fig.	
Amount Due		WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.	
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